

Form PTO 1449
(Modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO. 245841US2	SERIAL NO. 10/722,527
APPLICANT Simon RYDER	
FILING DATE November 28, 2003	GROUP

LIST OF REFERENCES CITED BY APPLICANT

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>MK</i>	AA	6,488,034	10/15/2002	M.- G. WANG, et al.			
	AB						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>MK</i>	AO	WO 02/35248	05/02/2002	WIPO		
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	S. A. RYDER, Conf. Record of 2002 IEEE Int. Symp. on Elect. Insulation, pages 187-190, XP-001162794, "METHODS FOR COMPARING FREQUENCY RESPONSE ANALYSIS MEASUREMENTS", April 2002
	AX	
	AY	
	AZ	

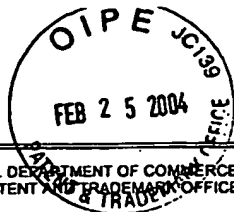
☐ Additional References sheet(s) attached

Examiner *M. Arambhaya*

Date Considered *1/27/05*

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 608; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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<i>MX</i>	AA	6,466,034	10/15/2002	M.- G. WANG, et al.			
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	AZ					

☐ Additional References sheet(s) attached

Examiner

M. Kramshov

Date Considered

8/18/05

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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